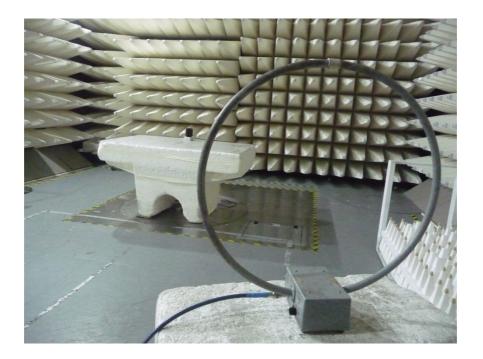


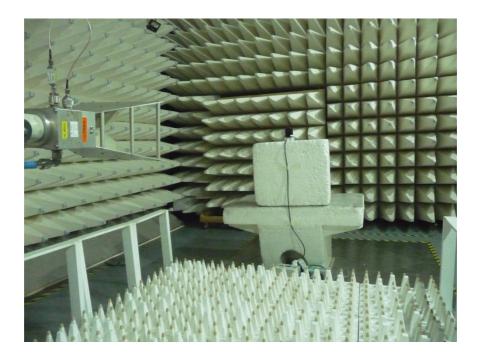
Photograph No.1 Setup for spurious emission field strength measurements in the anechoic chamber below 30 MHz



Photograph No.2 Setup for carrier and spurious emission field strength measurements in the anechoic chamber in 30 – 1000 MHz range



Photograph No.3 Setup for spurious emission field strength measurements in the anechoic chamber above 1000 MHz range





Photograph No.4 Setup for OBW, emission mask measurements



Photograph No.5 Setup for frequency stability measurements



Photograph No.6 Setup for transient frequency behavior measurements